

### N-Channel Enhancement Mode Power MOSFET

### **General Description**

The YMP200N08 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

### **Features**

- $V_{DS}$ =80V;  $I_D$ =200A@  $V_{GS}$ =10V;  $R_{DS(ON)}$ < 3 m $\Omega$  @  $V_{GS}$  =10V
- Special process technology for high ESD capability
- Special designed for Convertors and power controls
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

### **Application**

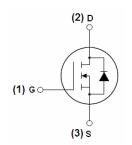
- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

### **Product Summary**

BV <sub>DSS</sub> typ.	80	>
R <sub>DS(ON)</sub> typ.	3	mΩ
max.	4	mΩ
I <sub>D</sub>	200	Α

### 100% UIS TESTED!





TO-247 top view

Schematic diagram

### **Package Marking And Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
YMP200N08	YMP200N08	TO-247	-	-	-

### Table 1. Absolute Maximum Ratings (TA=25℃)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage (V <sub>GS</sub> =0V)	V <sub>DS</sub>	80	V	
Gate-Source Voltage (V <sub>DS</sub> =0V)	V <sub>GS</sub>	±25	V	
Drain Current (DC) at Tc=25℃	I <sub>D (DC)</sub>	200	А	
Drain Current (DC) at Tc=100℃	I <sub>D (DC)</sub>	130	А	
Drain Current-Continuous@ Current-Pulsed (Note 1)	I <sub>DM (pluse)</sub>	430	Α	
Maximum Power Dissipation(Tc=25℃)	P <sub>D</sub>	300	W	
Derating factor		1.33	W/℃	
Single pulse avalanche energy (Note 2)	E <sub>AS</sub>	2000	mJ	
Operating Junction and Storage Temperature Range	$T_{J}$ , $T_{STG}$	-55 To 175	°C	

Notes 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2.EAS condition: Tj=25°C,VDD=28V,VG=10V,L=1mH ,R  $_{g}=25\Omega$ ;



**Table 2. Thermal Characteristic** 

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Note2)	R <sub>thJC</sub>	0.75	°C/W

 Table 3. Electrical Characteristics (TA=25 ℃ unless otherwise noted)

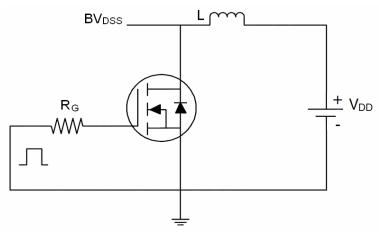
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	80			V
Zero Gate Voltage Drain Current(Tc=25℃)	I <sub>DSS</sub>	V <sub>DS</sub> =-24V,V <sub>GS</sub> =0V			1	μΑ
Gate-Body Leakage Current	I <sub>DSS</sub>	V <sub>GS</sub> =±25V,V <sub>DS</sub> =0V			± <b>10</b> 0	μA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	2	-	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =40A		3	4	mΩ
Dynamic Characteristics						
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =25V,I <sub>D</sub> =40A	50			S
Input Capacitance	C <sub>lss</sub>	\/ -20\/\/ -0\/		5000		PF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ =30V, $V_{GS}$ =0V, F=1.0MHz		860		PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.UIVIEZ		480		PF
Total Gate Charge	$Q_g$	V <sub>DS</sub> =30V,I <sub>D</sub> =40A,		106		nC
Gate-Source Charge	$Q_{gs}$	$V_{DS}=30V,I_{D}=40A,$ $V_{GS}=10V$		20		nC
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> -10V		35		nC
Switching times						
Turn-on Delay Time	t <sub>d(on)</sub>			34	50	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =30 $V$ , $I_{D}$ =1 $A$ , $R_{L}$ =30 $\Omega$		30	46	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{G}$ =4 $\Omega$		124	200	nS
Turn-Off Fall Time	t <sub>f</sub>			64	116	nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I <sub>SD</sub>				40	Α
Forward on voltage <sup>(Note 3)</sup>	V <sub>SD</sub>	Tj=25°C,I <sub>SD</sub> =20A,V <sub>GS</sub> =0V		0.8	1.3	V
Reverse Recovery Time <sup>(Note 1)</sup>	t <sub>rr</sub>	Ti=25°C L =40A di/dt=400A/vo		74		nS
Reverse Recovery Charge	Q <sub>rr</sub>	- Tj=25°C,I <sub>F</sub> =40A,di/dt=100A/μs		140		nC
Forward Turn-on Time	t <sub>on</sub>	Intrinsic turn-on time is negligible(turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

Notes 3.Pulse Test: Pulse Width ≤ 300 $\mu$ s, Duty Cycle ≤ 2%, R  $_{\text{G}}$  =25  $\Omega$ , Starting Tj=25  $^{\circ}$ C

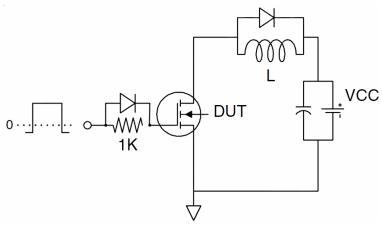


# **Test circuit**

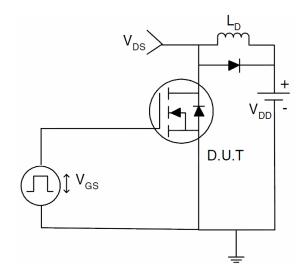
## 1) E<sub>AS</sub> test Circuits



### 2) Gate charge test Circuit:



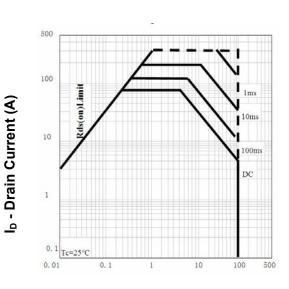
### 3) Switch Time Test Circuit:





# **Typical Characteristics**

### **Safe Operation Area**

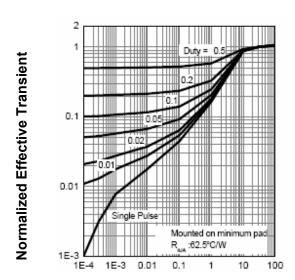


V<sub>DS</sub> - Drain-Source Voltage (V)

# 220 210 180 160 140 120 100 100 80 40 Limited By Package 20 0 Tc=25°C,Vg=10v 0 20 40 60 80 100 120 140 160 180

T<sub>i</sub> - Junction Temperature (°C)

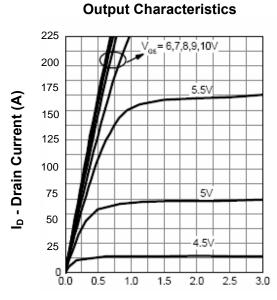
### **Thermal Transient Impedance**



**Square Wave Pulse Duration (sec)** 

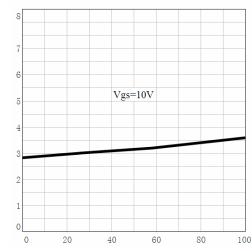


# **Typical Characteristics (Cont.)**



V<sub>DS</sub> - Drain-Source Voltage (V)

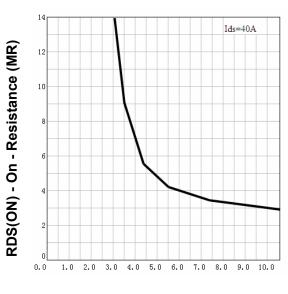
**Drain-Source On Resistance** 



R<sub>DS(ON)</sub> - On Resistance (mΩ)

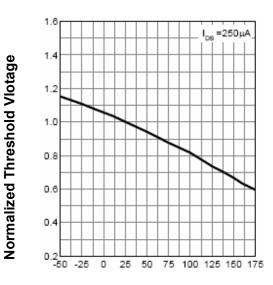
I<sub>D</sub> - Drain Current (A)

### **Drain-Source On Resistance**



VGS - Gate - Source Voltage (V)

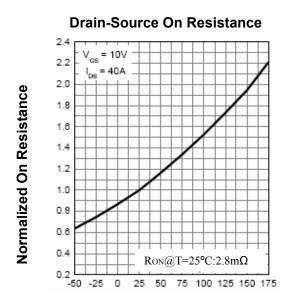
### **Gate Threshold Voltage**



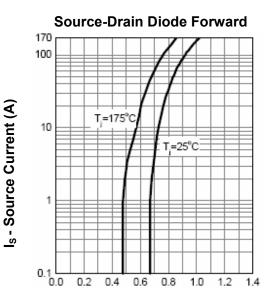
Tj - Junction Temperature (°C)



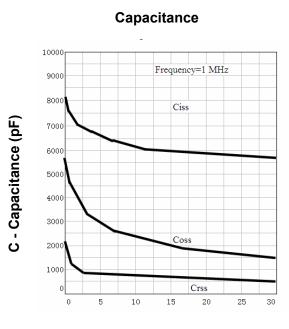
# **Typical Characteristics (Cont.)**



T<sub>j</sub> - Junction Temperature (°C)



V<sub>SD</sub> - Source-Drain Voltage (V)



V<sub>DS</sub> - Drain-Source Voltage (V)

